

<b>Notice of References Cited</b>	Application/Control No. 10/675,348	Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner JOHN Wahnkyo LEE	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,780,613 A	10-1988	Berstein et al.	250/343
*	C	US-5,033,015 A	07-1991	Zwirn, Robert	702/116
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagasawa et al., "Application of Fourier Transform Infrared Emission Spectrometry to Surface Analysis," March/April 1984, Vol. 38, 168-173
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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